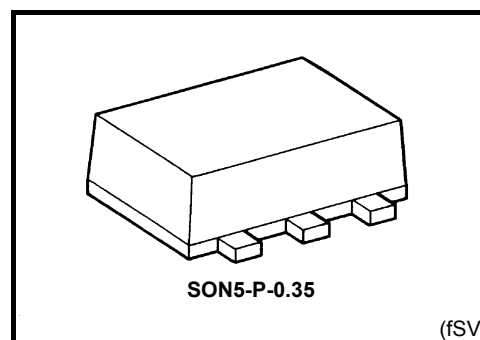


TC7SG00AFS

2 Input NAND Gate

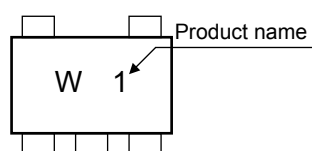
Features

- High-level output current: $I_{OH}/I_{OL} = \pm 8 \text{ mA (min)}$
at $V_{CC} = 3.0 \text{ V}$
- High-speed operation: $t_{pd} = 2.5 \text{ ns (typ.)}$
at $V_{CC} = 3.3 \text{ V}, 15\text{pF}$
- Operating voltage range: $V_{CC} = 0.9\sim 3.6 \text{ V}$
- 5.5-V tolerant inputs.

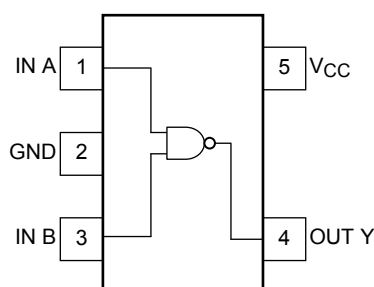


Weight: 0.001 g (typ.)

Marking



Pin Assignment (top view)



Absolute Maximum Ratings ($T_a = 25^\circ\text{C}$)

Characteristics	Symbol	Value	Unit
Power supply voltage	V_{CC}	$-0.5\sim 4.6$	V
DC input voltage	V_{IN}	$-0.5\sim 7.0$	V
DC output voltage	V_{OUT}	$-0.5\sim V_{CC} + 0.5$	V
Input diode current	I_{IK}	-20	mA
Output diode current	I_{OK}	± 20 (Note 1)	mA
DC output current	I_{OUT}	± 25	mA
DC V_{CC} /ground current	I_{CC}	± 50	mA
Power dissipation	P_D	50	mW
Storage temperature	T_{stg}	$-65\sim 150$	$^\circ\text{C}$

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

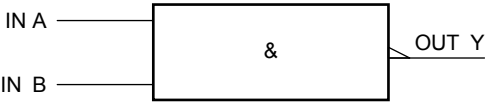
Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc.).

Note 1: $V_{OUT} < GND$, $V_{OUT} > V_{CC}$

Truth Table

A	B	Y
L	L	H
L	H	H
H	L	H
H	H	L

IEC Logic Symbol



Operating Ranges

Characteristics	Symbol	Value	Unit
Power supply voltage	V _{CC}	0.9~3.6	V
Input voltage	V _{IN}	0~5.5	V
Output voltage	V _{OUT}	0~V _{CC}	V
Output Current	I _{OH} /I _{OL}	±8.0 (Note 2)	mA
		±4.0 (Note 3)	
		±3.0 (Note 4)	
		±1.7 (Note 5)	
		±0.3 (Note 6)	
		±0.02 (Note 7)	
Operating temperature	T _{opr}	−40~85	°C
Input rise and fall time	dt/dV	0~10 (Note 8)	ns/V

- Note 2: V_{CC} = 3.0~3.6 V
- Note 3: V_{CC} = 2.3~2.7 V
- Note 4: V_{CC} = 1.65~1.95 V
- Note 5: V_{CC} = 1.4~1.6 V
- Note 6: V_{CC} = 1.1~1.3 V
- Note 7: V_{CC} = 0.9 V
- Note 8: V_{IN} = 0.8~2.0 V, V_{CC} = 3.0 V

DC Electrical Characteristics

Characteristics	Symbol	Test Condition		Ta = 25°C				Ta = -40~85°C		Unit
				V _{CC} (V)	Min	Typ.	Max	Min	Max	
High-level input voltage	V _{IH}	—		0.9	V _{CC}	—	—	V _{CC}	—	V
				1.1~1.3	V _{CC} × 0.7	—	—	V _{CC} × 0.7	—	
				1.4~1.6	V _{CC} × 0.65	—	—	V _{CC} × 0.65	—	
				1.65~1.95	V _{CC} × 0.65	—	—	V _{CC} × 0.65	—	
				2.3~2.7	1.7	—	—	1.7	—	
				3.0~3.6	2.0	—	—	2.0	—	
Low-level input voltage	V _{IL}	—		0.9	—	—	GND	—	GND	V
				1.1~1.3	—	—	V _{CC} × 0.3	—	V _{CC} × 0.3	
				1.4~1.6	—	—	V _{CC} × 0.35	—	V _{CC} × 0.35	
				1.65~1.95	—	—	V _{CC} × 0.35	—	V _{CC} × 0.35	
				2.3~2.7	—	—	0.7	—	0.7	
				3.0~3.6	—	—	0.8	—	0.8	
High-level output voltage	V _{OH}	V _{IN} = V _{IH} or V _{IL}	I _{OH} = -0.02 mA	0.9	0.75	—	—	0.75	—	V
			I _{OH} = -0.3 mA	1.1~1.3	V _{CC} × 0.75	—	—	V _{CC} × 0.75	—	
			I _{OH} = -1.7 mA	1.4~1.6	V _{CC} × 0.75	—	—	V _{CC} × 0.75	—	
			I _{OH} = -3.0 mA	1.65~1.95	V _{CC} -0.45	—	—	V _{CC} -0.45	—	
			I _{OH} = -4.0 mA	2.3~2.7	2.0	—	—	2.0	—	
			I _{OH} = -8.0 mA	3.0~3.6	2.48	—	—	2.48	—	
Low-level output voltage	V _{OL}	V _{IN} = V _{IH}	I _{OL} = 0.02 mA	0.9	—	—	0.1	—	0.1	V
			I _{OL} = 0.3 mA	1.1~1.3	—	—	V _{CC} × 0.25	—	V _{CC} × 0.25	
			I _{OL} = 1.7 mA	1.4~1.6	—	—	V _{CC} × 0.25	—	V _{CC} × 0.25	
			I _{OL} = 3.0 mA	1.65~1.95	—	—	0.45	—	0.45	
			I _{OL} = 4.0 mA	2.3~2.7	—	—	0.4	—	0.4	
			I _{OL} = 8.0 mA	3.0~3.6	—	—	0.4	—	0.4	
Input leakage current	I _{IN}	V _{IN} = 0~5.5V		0~3.6	—	—	±0.1	—	±1.0	μA
Quiescent supply current	I _{CC}	V _{IN} = V _{CC} or GND		3.6	—	—	1.0	—	10.0	μA

AC Electrical Characteristics (input $t_r = t_f = 3\text{ ns}$)

Characteristics	Symbol	Test Condition	Ta = 25°C			Ta = -40~85°C		Unit
			V _{CC} (V)	Min	Typ.	Max	Min	Max
Propagation delay time	t_{PLH} t_{PHL}	$C_L = 10\text{ pF}$, $R_L = 1\text{ M}\Omega$	0.9	—	26.9	—	—	—
			1.1~1.3	—	10.9	18.4	1.0	34.2
			1.4~1.6	—	5.9	8.5	1.0	10.0
			1.65~1.95	—	4.5	6.2	1.0	6.7
			2.3~2.7	—	2.9	3.9	1.0	4.4
			3.0~3.6	—	2.2	3.1	1.0	3.7
		$C_L = 15\text{ pF}$, $R_L = 1\text{ M}\Omega$	0.9	—	30.0	—	—	—
			1.1~1.3	—	12.0	21.5	1.0	37.2
			1.4~1.6	—	6.5	9.3	1.0	11.2
			1.65~1.95	—	5.0	6.9	1.0	7.1
			2.3~2.7	—	3.2	4.4	1.0	5.0
			3.0~3.6	—	2.5	3.4	1.0	3.9
		$C_L = 30\text{ pF}$, $R_L = 1\text{ M}\Omega$	0.9	—	45.0	—	—	—
			1.1~1.3	—	18.0	29.6	1.0	56.0
			1.4~1.6	—	8.9	13.1	1.0	15.9
			1.65~1.95	—	6.9	9.2	1.0	9.6
			2.3~2.7	—	4.4	5.7	1.0	6.1
			3.0~3.6	—	3.5	4.4	1.0	4.8
Input capacitance	C_{IN}	—	3.6	—	3	—	—	pF
Power dissipation capacitance	C_{PD}	(Note9)	0.9~3.6	—	6	—	—	pF

Note 9: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

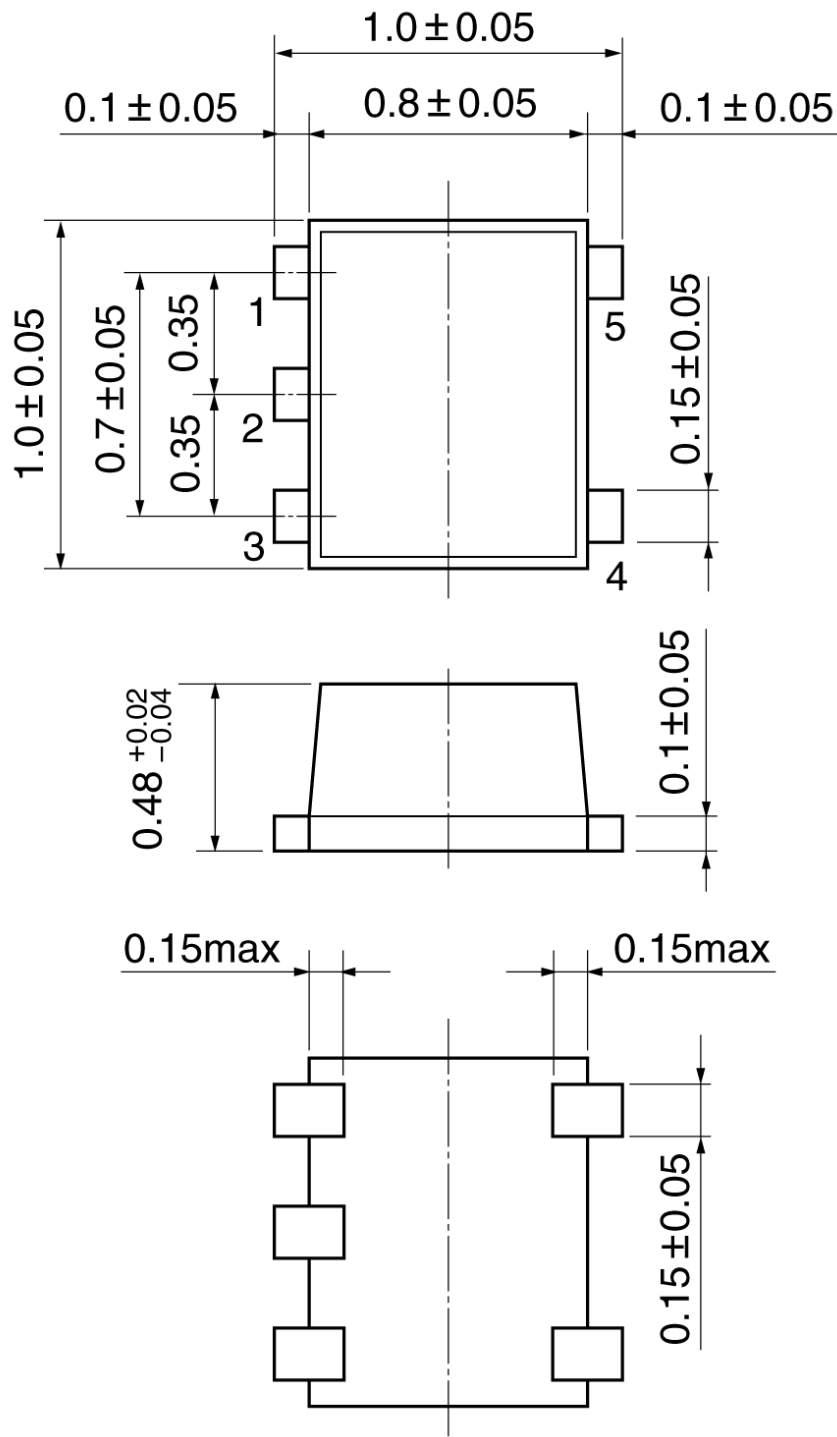
Average operating current can be obtained by the equation:

$$I_{CC(\text{opr})} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$$

Package Dimensions

SON5-P-0.35

Unit:mm



Weight: 0.001 g (typ.)

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20070701-EN GENERAL

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